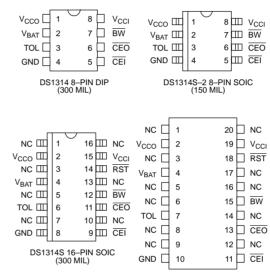


3V Nonvolatile Controller with Lithium Battery Monitor

FEATURE

- Converts CMOS SRAM into nonvolatile memory
- Unconditionally write-protects SRAM when V_{CC} is out of tolerance
- Automatically switches to battery-backup supply when V_{CC} power failure occurs
- Monitors voltage of a lithium cell and provides advanced warning of impending battery failure
- Signals low-battery condition on active low Battery Warning output signal
- Automatic V_{CC} power–fail detection for 3.0V or 3.3V power supplies
- Space-saving 8-pin DIP and SOIC packages
- Optional 16-pin SOIC and 20-pin TSSOP versions reset processor when power failure occurs and hold processor in reset during system power-up
- Industrial temperature range of -40°C to +85°C.

PIN ASSIGNMENT



DS1314E 20-PIN TSSOP

DESCRIPTION

The DS1314 Nonvolatile Controller with Battery Monitor is a CMOS circuit which solves the application problem of converting CMOS RAM into nonvolatile memory. Incoming power is monitored for an out–of–tolerance condition. When such a condition is detected, chip enable is inhibited to accomplish write protection and the battery is switched on to supply the RAM with uninterrupted power. Special circuitry uses a low–leakage CMOS process which affords precise voltage detection at extremely low battery consumption.

PIN DESCRIPTION

V_{CCI} - Power Supply Input

V_{CCO} - SRAM Power Supply Output

V_{BAT} - Backup Battery Input

CEI - Chip Enable Input

CEO - Chip Enable Output

TOL - V_{CC} Tolerance Select

BW - Battery Warning Output (Open Drain)

RST - Reset Output (Open Drain)

GND - Ground

NC - No Connection

In addition to battery–backup support, the DS1314 performs the important function of monitoring the remaining capacity of the lithium battery and providing a warning before the battery reaches end–of–life. Because the open–circuit voltage of a lithium backup battery remains relatively constant over the majority of its life, accurate battery monitoring requires loaded–battery voltage measurement. The DS1314 performs such measurement by periodically comparing the voltage of the battery as it supports an internal resistive load with a carefully selected reference voltage. If the battery voltage falls below the reference voltage under such conditions, the battery will soon reach end–of–life. As a result, the Battery Warning pin is activated to signal the need for battery replacement.

MEMORY BACKUP

The DS1314 performs all the circuit functions required to provide battery–backup for an SRAM. First, the device provides a switch to direct power from the battery or the system power supply (V_{CCI}). Whenever V_{CCI} is less than the switch point V_{SW} and V_{CCI} is less than the battery voltage V_{BAT}, the battery is switched in to provide backup power to the SRAM. This switch has voltage drop of less than 0.2 volts.

Second, the DS1314 handles power failure detection and SRAM write-protection. V_{CCI} is constantly monitored, and when the supply goes out of tolerance, a precision comparator detects power failure and inhibits chip enable output (CEO) in order to write-protect the SRAM. This is accomplished by holding CEO to within 0.2 volts of V_{CCO} when V_{CCI} is out of tolerance. If CEI is (active) low at the time that power failure is detected, the CEO signal is kept low until CEI is brought high again. Once CEI is brought high, CEO is taken high and held high until after V_{CCI} has returned to its nominal voltage level. If CEI is not brought high by 1.5 μs after power failure is detected, CEO is forced high at that time. This specific scheme for delaying write protection for up to 1.5 µs guarantees that any memory access in progress when power failure occurs will complete properly. power failure detection occurs at 3.0V nominal (3.3V supply) when the TOL pin is wired to GND or at 2.7V nominal (3.0V supply) when TOL is connected to V_{CCO}.

BATTERY VOLTAGE MONITORING

The DS1314 automatically performs periodic battery voltage monitoring at a factory–programmed time interval of 24 hours. Such monitoring begins within $t_{\rm REC}$

after V_{CCI} rises above $V_{CCTP_{\!\scriptscriptstyle I}}$ and is suspended when power failure occurs.

After each 24 hour period (t_{BTCN}) has elapsed, the DS1314 connects V_{BAT} to an internal 1.2 M Ω test resistor (R_{INT}) for one second (t_{BTPW}). During this one second, if V_{BAT} falls below the factory–programmed battery voltage trip point (V_{BTP}), the battery warning output \overline{BW} is asserted. While \overline{BW} is active battery testing will be performed with period t_{BTCW} to detect battery removal and replacement. Once asserted, \overline{BW} remains active until the battery is physically removed and replaced by a fresh cell. The battery is still retested after each V_{CC} power–up, however, even if \overline{BW} was active on power–down. If the battery is found to be higher than V_{BTP} during such testing, \overline{BW} is deasserted and regular 24–hour testing resumes. \overline{BW} has an open–drain output driver.

Battery replacement following \overline{BW} activation is normally done with V_{CCI} nominal so that SRAM data is not lost. During battery replacement, the minimum time duration between old battery detachment and new battery attachment (t_{BDBA}) \underline{must} be met or \overline{BW} will not deactivate following attachment of the new battery. Should \overline{BW} not deactivate for this reason, the new battery can be detached for t_{BDBA} and then re–attached to clear \overline{BW}

NOTE: The DS1314 cannot constantly monitor an attached battery because such monitoring would drastically reduce the life of the battery. As a result, the DS1314 only tests the battery for one second out of every 24 hours and does not monitor the battery in any way between tests. If a good battery (one that has not been previously flagged with \overline{BW}) is removed between battery tests, the DS1314 may not immediately sense the removal and may not activate \overline{BW} until the next scheduled battery test. If a battery is then reattached to the DS1314, the battery may not be tested until the next scheduled test.

NOTE: Battery monitoring is only an useful technique when testing can be done regularly over the entire life of a lithium battery. Because the DS1314 only performs battery monitoring when V_{CC} is nominal, systems which are powered—down for excessively long periods can completely drain their lithium cells without receiving any advanced warning. To prevent such an occurrence, systems using the DS1314 battery monitoring feature should be powered—up periodically (at least once every

few months) in order to perform battery testing. Furthermore, anytime \overline{BW} is activated on the first battery test after a power–up, data integrity should be checked via checksum or other technique.

200 ms nominal (t_{RPU}). This reset period is sufficiently long to prevent system operation during power—on transients and to allow t_{REC} to expire. \overline{RST} has an opendrain output driver.

POWER MONITORING

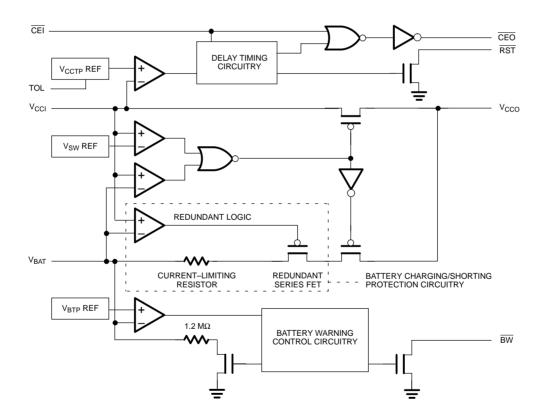
DS1314S and DS1314E varieties have an additional reset pin. These varieties detect out–of–tolerance power supply conditions and warn a processor–based system of impending power failure. When $V_{\rm CCI}$ falls below the trip point level defined by the TOL pin ($V_{\rm CCTP}$), the $V_{\rm CCI}$ comparator activates the reset signal $\overline{\rm RST}.$ Reset occurs at 3.0V nominal (3.3V supply) when the TOL pin is connected to GND or at 2.7V nominal (3.0V supply) when TOL is connected to $V_{\rm CCO}$.

 \overline{RST} also serves as a power–on reset during power–up. After V_{CCI} exceeds V_{CCTP} , \overline{RST} will be held active for

FRESHNESS SEAL MODE

When the battery is first attached to the DS1314 without V_{CC} power applied, the device does not immediately provide battery–backup power on V_{CCO} . Only after V_{CCI} exceeds V_{CCTP} and later falls below both V_{SW} and V_{BAT} will the DS1314 leave Freshness Seal Mode and provide battery–backup power. This mode allows a battery to be attached during manufacturing but not used until after the system has been activated for the first time. As a result, no battery energy is drained during storage and shipping.

FUNCTIONAL BLOCK DIAGRAM Figure 1



ABSOLUTE MAXIMUM RATINGS* Voltage on Any Pin Relative to Ground -0.5V to +7.0V Operating Temperature Storage Temperature -40°C to +85°C -55°C to +125°C Soldering Temperature 260°C for 10 seconds

RECOMMENDED DC OPERATING CONDITIONS

(-40°C to +85°C)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Supply Voltage TOL=GND	V _{CCI}	3.0	3.3	3.6	V	1
Supply Voltage TOL=V _{CCO}	V _{CCI}	2.7	3.0	3.3	V	1
Battery Supply Voltage	V _{BAT}	2.0		6.0	V	1
Logic 1 Input	V _{IH}	2.0		V _{CCI} +0.3	V	1, 12
Logic 0 Input	V _{IL}	-0.3		+0.8	V	1, 12

DC ELECTRICAL CHARACTERISTICS

 $(-40^{\circ}\text{C to } +85^{\circ}\text{C}; \text{V}_{\text{CCI}} = \geq \text{V}_{\text{CCTP}})$

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Operating Current (TTL inputs)	I _{CC1}		50	200	μΑ	2
Operating Current (CMOS inputs)	I _{CC2}		30	100	μΑ	2, 5
RAM Supply Current $(V_{CCO} \ge V_{CCI} - 0.2V)$	V _{CC1}			80	mA	3
RAM Supply Current (V _{CCO} ≥ V _{CCI} −0.3V)	I _{CCO1}			140	mA	4
V _{CC} Trip Point (TOL=GND)	V _{CCTP}	2.8	2.9	3.0	V	1
V _{CC} Trip Point (TOL=V _{CCO})	V _{CCTP}	2.5	2.6	2.7	V	1
V _{BAT} Trip Point	V_{BTP}	2.5	2.6	2.7	V	1
V _{CC} /V _{BAT} Switch Point (TOL=GND)	V _{SW}	2.6	2.7	2.8	V	1
V _{CC} /V _{BAT} Switch Point (TOL=V _{CCO})	V _{SW}	2.4	2.5	2.6	V	1
Output Current @ 2.2V	I _{OH}	-1			mA	7, 10
Output Current @ 0.4V	I _{OL}			4	mA	7, 10
Input Leakage	I _{IL}	-1.0		+1.0	μΑ	
Output Leakage	I _{LO}	-1.0		+1.0	μΑ	
Battery Monitoring Test Load	R _{INT}	0.8	1.2	1.5	ΜΩ	

^{*} This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

DC ELECTRICAL CHARACTERISTICS

(-40°C to +85°C; $V_{CCI} < V_{BAT}$; $V_{CCI} < V_{SW}$)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Battery Current	I _{BAT}			100	nA	2
Battery-Backup Current	I _{CCO2}			500	μΑ	6
Supply Voltage	V _{cco}	V _{BAT} -0.2			V	1
CEO Output	V _{OHL}	V _{BAT} -0.2			V	1, 8

CAPACITANCE $(t_A=25^{\circ}C)$

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Capacitance (CEI, TOL)	C _{IN}			7	pF	
Output Capacitance (CEO, BW, RST)	C _{OUT}			7	pF	

AC ELECTRICAL CHARACTERISTICS

(–40°C to +85°C; V_{CCI} ≥ V_{CCTP})

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
CEI to CEO Propagation Delay	t _{PD}		12	20	ns	
CE Pulse Width	t _{CE}			1.5	μs	11
V _{CC} Valid to End of Write Protection	t _{REC}		12	125	ms	9
V _{CC} Valid to CEI Inactive	t _{PU}			2	ms	
V _{CC} Valid to RST Inactive	t _{RPU}	150	200	350	ms	10
V _{CC} Valid to BW Valid	t _{BPU}			1	S	10

AC ELECTRICAL CHARACTERISTICS

 $(-40^{\circ}\text{C to } +85^{\circ}\text{C}; V_{\text{CCI}} < V_{\text{CCTP}})$

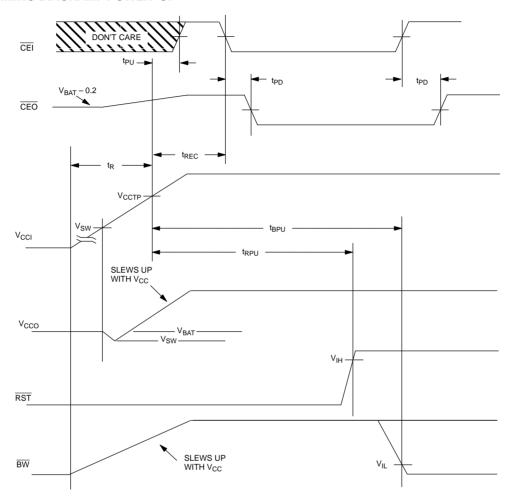
				(CI COIF
PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
V _{CC} Slew Rate	t _F	150			μs	
V _{CC} Fail Detect to RST Active	t _{RPD}		5	15	μs	10
V _{CC} Slew Rate	t _R	150			μs	

AC ELECTRICAL CHARACTERISTICS

(-40°C to +85°C; $V_{CCI} \ge V_{CCTP}$)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Battery Test to BW Active	t _{BW}			1	s	10
Battery Test Cycle–Normal	t _{BTCN}		24		hr	
Battery Test Cycle–Warning	t _{BTCW}		5		s	
Battery Test Pulse Width	t _{BTPW}			1	S	
Battery Detach to Battery Attach	t _{BDBA}	7			s	
Battery Attach to BW Inactive	t _{BABW}	·		1	S	10

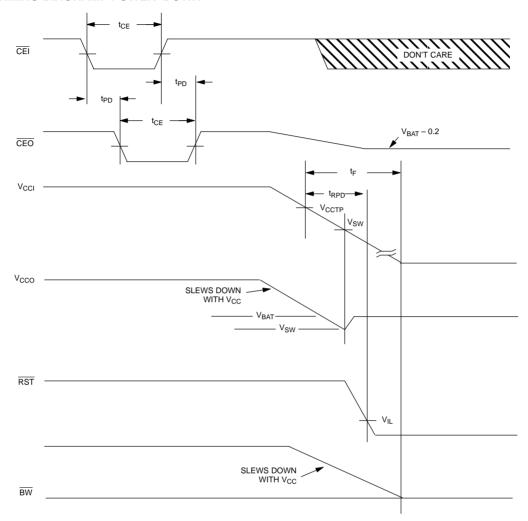
TIMING DIAGRAM: POWER-UP



NOTE:

If $V_{BAT} < V_{SW}$, V_{CCO} will begin to slew with V_{CCI} when $V_{CCI} = V_{BAT}$.

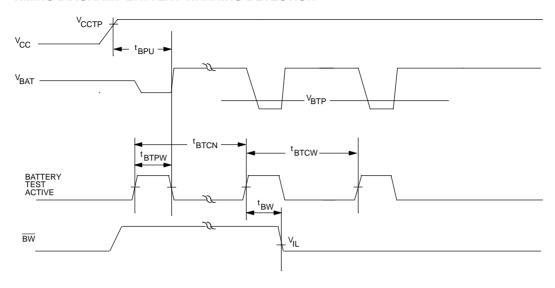
TIMING DIAGRAM: POWER-DOWN



NOTE:

If $V_{BAT} < V_{SW}$, V_{CCO} will slew down with V_{CCI} until $V_{CCI} = V_{BAT}$.

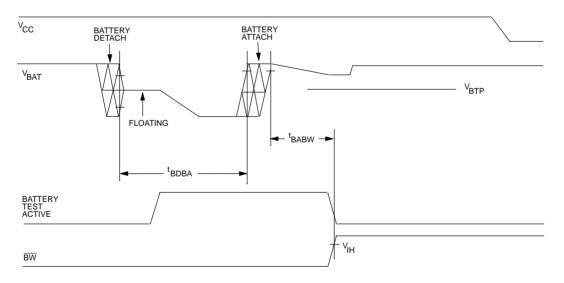
TIMING DIAGRAM: BATTERY WARNING DETECTION



NOTE:

 t_{BW} is measured from the expiration of the internal timer to the activation of the battery warning output $\overline{\text{BW}}$.

TIMING DIAGRAM: BATTERY REPLACEMENT



NOTES:

- 1. All voltages referenced to ground.
- 2. Measured with outputs open circuited.
- 3. I_{CCO1} is the maximum average load which the DS1314 can supply to attached memories at V_{CC0} ≥ V_{CCI} −0.2V.
- 4. I_{CCO1} is the Maximum average load which the DS1314 can supply to attached memories at V_{CCO} ≥ V_{CCI} −0.3V.
- 5. All inputs within 0.3V of ground or V_{CCI}.
- 6. I_{CCO2} is the maximum average load current which the DS1314 can supply to the memories in the battery–backup mode.
- 7. Measured with a load as shown in Figure 1.
- 8. Chip Enable Output CEO can only sustain leakage current in the battery-backup mode.
- 9. $\overline{\text{CEO}}$ will be held high for a time equal to t_{REC} after V_{CCI} crosses V_{CCTP} on power–up.
- 10. \overline{BW} and \overline{RST} are open drain outputs and, as such, cannot source current. External pull–up resistors should be connected to these pins for proper operation. Both \overline{BW} and \overline{RST} can sink 10 mA.
- 11. t_{CE} maximum must be met to ensure data integrity on power–down.
- 12. In battery-backup mode, inputs must never be below ground or above V_{CCO}.

DC TEST CONDITIONS

Outputs Open All voltages are referenced to ground

AC TEST CONDITIONS

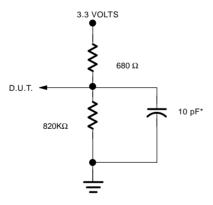
Output Load: See below Input Pulse Levels: 0 – 3.0V

Timing Measurement Reference Levels

Input: 1.5V Output: 1.5V

Input pulse Rise and Fall Times: 5 ns

OUTPUT LOAD Figure 1



* INCLUDING SCOPE AND JIG CAPACITANCE

DATA SHEET REVISION SUMMARY

The following represent the key differences between 12/16/96 and 06/12/97 version of the DS1314 data sheet. Please review this summary carefully.

- 1. Changed V_{BAT} max to 6V
- 2. Changed V_{CCTP} values to 2.8 3.0V (TOL = GND) and 2.5 2.7V (TOL = V_{CC})
- 3. Changed $t_{\mbox{\footnotesize BABW}}$ from 7s to 1s max
- 4. Changed block diagram to show U L compliance

The following represent the key differences between 06/12/97 and 08/29/97 version of the DS1314 data sheet. Please review this summary carefully.

- 1. Changed AC test conditions
- 2. Changed tpD to 20 max & 12 typ

The following represent the key differences between 08/29/97 and 12/16/97 version of the DS1314 data sheet. Please review this summary carefully.

- 1. Change V_{CCI} mins from 3.05V to 3.0V (TOL=GND) and from 275V to 2.7V (TOL= V_{CCD}) (this should have been done on 06/12/97 revision but was overlooked).
- 2. Specified Input Capacitance as being only for $\overline{\text{CEO}}$, $\overline{\text{TOL}}$ and Output Capacitance as being only for $\overline{\text{CEO}}$, $\overline{\text{BW}}$ and $\overline{\text{RST}}$. This is not a change but rather clarification.
- 3. Removed "preliminary" from title bar.